

Search Notes

Application/Control No.

10/629,917

Examiner

VAN T. PHAM

Applicant(s)/Patent under
Reexamination

YONEZAWA, MINORU

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
369	44.29, 44.32.	7/19/2006 <i>updated on 12/19/06</i>	VP <i>vp</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPUB	text search	12/19/2006	VP
Interference search (see search history printout)			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369 (text search only see search history printout).	12/19/2006	VP